

**Search Notes**

Application/Control No.

09/780,308

Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

SHIH ET AL.

Art Unit

709

**SEARCHED**

Class	Subclass	Date	Examiner
709	229	3/2/2006	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	3/2/2006	DB
Google, IEEE	3/2/2006	DB